COMPLEMENTARY 40V ENHANCEMENT MODE MOSFET

SUMMARY

N-Channel = $V_{(BR)DSS}$ = 40V : $R_{DS(on)}$ = 0.05 Ω ; I_D = 5.2A

P-Channel = $V_{(BR)DSS}$ = -40V : $R_{DS(on)}$ = 0.06 Ω ; I_D = -4.7A

DESCRIPTION

This new generation of trench MOSFETs from Zetex utilises a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.

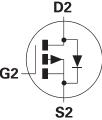


- Low on-resistance
- · Fast switching speed
- Low threshold
- · Low gate drive
- Low profile SOIC package

APPLICATIONS

- Motor drive
- LCD backlighting

D1 G1 G2



SO8

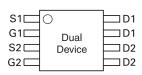
ORDERING INFORMATION

DEVICE	REEL SIZE	TAPE WIDTH	QUANTITY PER REEL
ZXMC4A16DN8TA	7″	12mm	500
ZXMC4A16DN8TC	13″	12mm	2,500

DEVICE MARKING

 ZXMC 4A16

PINOUT



TOP VIEW



ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	N-channel	P-channe	UNIT
Drain-source voltage	V _{DSS}	40	-40	V
Gate-source voltage	V _{GS}	±20	±20	V
Continuous drain current	I _D			
$(V_{GS} = 10V; T_A = 25^{\circ}C)^{(b)(d)}$		5.2	-4.7	Α
$(V_{GS} = 10V; T_A = 70^{\circ}C)^{(b)(d)}$		4.1	-3.8	Α
$(V_{GS} = 10V; T_A = 25^{\circ}C)^{(a)(d)}$		4.0	-3.6	А
Pulsed drain current ^(c)	I _{DM}	24	-23	А
Continuous source current (body diode) (b)	I _S	2.5	2.3	А
Pulsed source current (body diode) (c)	I _{SM}	24	23	А
Power dissipation at T _A =25°C ^{(a) (d)}	P _D	1.25		W
Linear derating factor		1	10	
Power dissipation at T _A =25°C ^{(a) (e)}	P _D	1	1.8	
Linear derating factor		1	14	
Power dissipation at T _A =25°C ^{(b) (d)}	P _D	2.1		W
Linear derating factor		17		mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to +150		°C

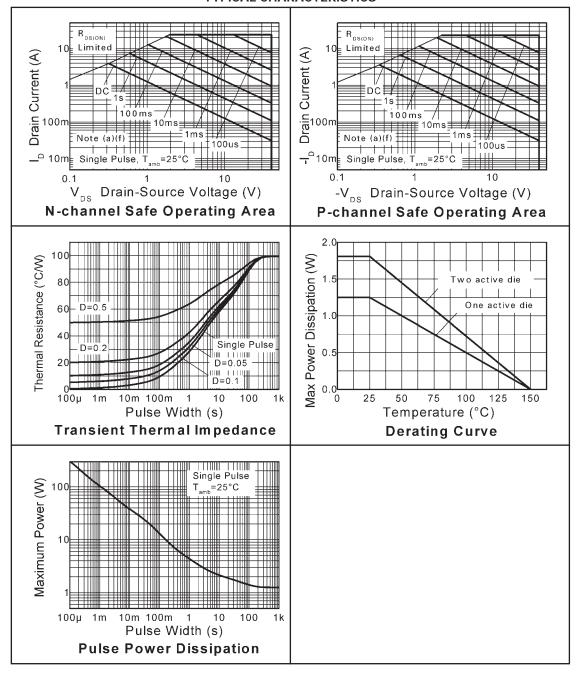
THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to ambient ^{(a) (d)}	$R_{\Theta JA}$	100	°C/W
Junction to ambient ^{(a) (e)}	$R_{\Theta JA}$	70	°C/W
Junction to ambient ^{(b) (d)}	$R_{\Theta JA}$	60	°C/W

NOTES

- (a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.
- (b) For a device surface mounted on FR4 PCB measured at $t \le 10$ sec.
- (c) Repetitive rating pulse width limited by maximum junction temperature. Pulse width 300us, d<= 0.02. Refer to Transient Thermal Impedance graph.
- (d) For device with one active die.
- (e) For device with two active die running at equal power.







ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated)

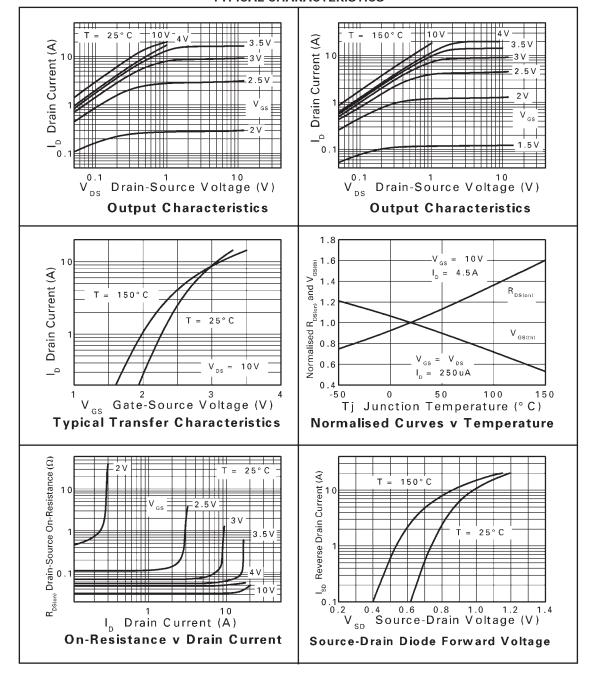
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	40			V	I _D = 250μA, V _{GS} =0V
Zero Gate Voltage Drain Current	I _{DSS}			0.5	μΑ	V _{DS} =40V, V _{GS} =0V
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-Source Threshold Voltage	V _{GS(th)}	1.0			V	I _D = 250mA, V _{DS} =V _{GS}
Static Drain-Source On-State Resistance (1)	R _{DS(on)}			0.050 0.075	Ω	V _{GS} = 10V, I _D = 4.5A V _{GS} = 4.5V, I _D = 3.2A
Forward Transconductance (1) (3)	9 _{fs}		8.6		S	V _{DS} = 15V, I _D = 4.5A
DYNAMIC (3)		•				
Input Capacitance	Ciss		770		pF	
Output Capacitance	Coss		92		pF	V _{DS} = 40V, V _{GS} =0V f=1MHz
Reverse Transfer Capacitance	Crss		61		pF	1 = 11011112
SWITCHING ^{(2) (3)}			•	•	•	
Turn-On-Delay Time	td(on)		3.3		ns	
Rise Time	tr		4.7		ns	2011 14
Turn-Off Delay Time	td(off)		29		ns	$V_{DD} = 30V, I_{D} = 1A$ $R_{G} \approx 6.0\Omega, V_{GS} = 10V$
Fall Time	tf		14		ns	11G =0.012, VGS- 10V
Total Gate Charge	Qg		17		nC	
Gate-Source Charge	Qgs		2.5		nC	V _{DS} = 30V, V _{GS} = 10V
Gate Drain Charge	Qgd		3.8		nC	I _D = 4.5A
SOURCE-DRAIN DIODE	1					•
Diode Forward Voltage ⁽¹⁾	VSD		0.8	0.95	V	T _j =25°C, I _S = 4.5A, V _{GS} =0V
Reverse Recovery Time ⁽³⁾	trr		20		ns	T _j =25°C, I _S = 2.5A,
Reverse Recovery Charge ⁽³⁾	Qrr		16		nC	di/dt=100A/μs

NOTES

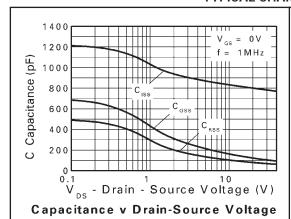
- (1) Measured under pulsed conditions. Pulse width $\leq 300 \mu s;$ duty cycle $\leq 2 \%.$
- (2) Switching characteristics are independent of operating junction temperature.
- (3) For design aid only, not subject to production testing.

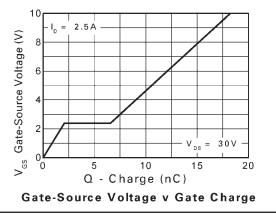


TYPICAL CHARACTERISTICS



ZETEX







ELECTRICAL CHARACTERISTICS (at T_{amb} = 25°C unless otherwise stated)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS
STATIC	1	•		'		1
Drain-Source Breakdown Voltage	V _{(BR)DSS}	-40			V	I _D = -250μA, V _{GS} =0V
Zero Gate Voltage Drain Current	I _{DSS}			-1.0	μΑ	V _{DS} = -40V, V _{GS} =0V
Gate-Body Leakage	I _{GSS}			100	nA	V _{GS} =±20V, V _{DS} =0V
Gate-Source Threshold Voltage	V _{GS(th)}	-1.0			V	I _D = -250μA, V _{DS} =V _{GS}
Static Drain-Source On-State Resistance (1)	R _{DS(on)}			0.060 0.100	Ω	V _{GS} = -10V, I _D = -3.8A V _{GS} = -4.5V, I _D = -2.9A
Forward Transconductance (1) (3)	9 _{fs}		6.8		S	V _{DS} = -15V, I _D = -3.8A
DYNAMIC (3)	1	1				1
Input Capacitance	C _{iss}		1000		pF	
Output Capacitance	C _{oss}		180		рF	V _{DS} = -20V, V _{GS} =0V f=1MHz
Reverse Transfer Capacitance	C _{rss}		160		pF	T = TIVITIZ
SWITCHING ^{(2) (3)}	•	•	•	•	•	
Turn-On-Delay Time	t _{d(on)}		3.7		ns	
Rise Time	t _r		5.5		ns	V _{DD} = -20V, I _D = -1A
Turn-Off Delay Time	t _{d(off)}		33		ns	$R_G \cong 6.0\Omega$, $V_{GS} = 10V$
Fall Time	t _f		18		ns	
Gate Charge	Qg		15		nC	V _{DS} = -20V, V _{GS} = -5V I _D = -3.8A
Total Gate Charge	Qg		26		nC	
Gate-Source Charge	Q _{gs}		3.2		nC	$V_{DS} = -20V, V_{GS} = -10V$ $I_{D} = -3.8A$
Gate Drain Charge	Q _{gd}		7.3		nC	1D2.0A
SOURCE-DRAIN DIODE	•		1			1
Diode Forward Voltage ⁽¹⁾	V _{SD}		-0.86	-0.95	V	T _j =25°C, I _S = -3.4A, V _{GS} =0V
Reverse Recovery Time ⁽³⁾	t _{rr}		27		ns	T _j =25°C, I _S = -3A,
Reverse Recovery Charge ⁽³⁾	Q _{rr}		25		nC	di/dt=100A/μs

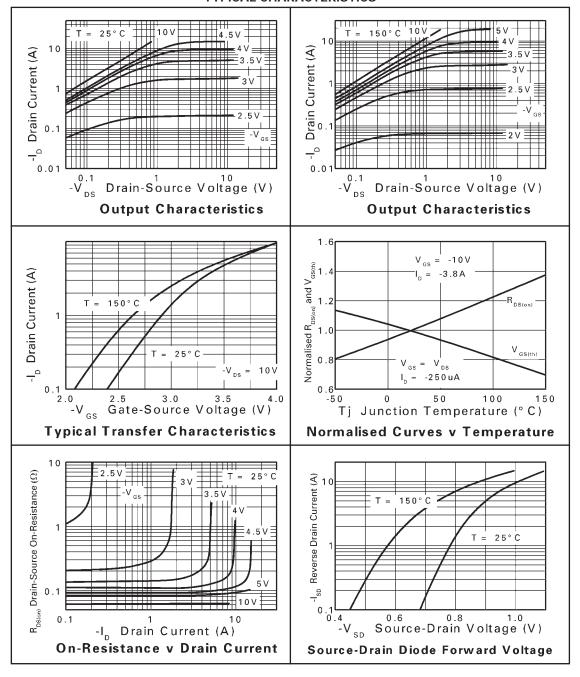
NOTES



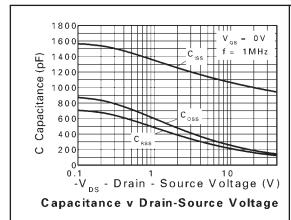
⁽¹⁾ Measured under pulsed conditions. Pulse width $\leq~300 \mu s;$ duty cycle $\leq 2\%.$

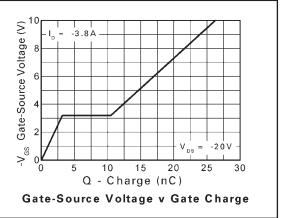
⁽²⁾ Switching characteristics are independent of operating junction temperature.

⁽³⁾ For design aid only, not subject to production testing.



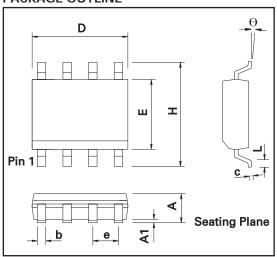








PACKAGE OUTLINE



Controlling dimensions are in millimeters. Approximate conversions are given in inches

PACKAGE DIMENSIONS

DIM	Millin	neters	Incl	hes	DIM -	Millimeters		Inches	
DIIVI	Min	Max	Min	Max	DIIVI	Min	Max	Min	Max
Α	1.35	1.75	0.053	0.069	е	1.27 BSC		0.050 BSC	
A1	0.10	0.25	0.004	0.010	b	0.33	0.51	0.013	0.020
D	4.80	5.00	0.189	0.197	С	0.19	0.25	0.008	0.010
Н	5.80	6.20	0.228	0.244	θ	0°	8°	0°	8°
Е	3.80	4.00	0.150	0.157	h	0.25	0.50	0.010	0.020
L	0.40	1.27	0.016	0.050	-	-	-	-	-

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